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Question Paper Code: 42461

B.E./B.Tech. DEGREE EXAMINATION, APRIL/MAY 2018

Sixth Semester

Electronics and Communication Engineering

EC2354 – VLSI DESIGN

(Common to Biomedical Engineering)

(Regulations 2008)

(Also Common to PTEC2354 – VLSI Design for B.E. (Part-Time) Fifth Semester – ECE – Regulations 2009)

Time: Three Hours

Maximum: 100 Marks

Answer ALL questions

PART - A

 $(10\times2=20 \text{ Marks})$

- 1. Define threshold voltage of a MOS transistor.
- 2. State the purpose of design rules.
- 3. Define logical effort.
- 4. What is meant by design or process corners?
- 5. State the logics by which low power circuit designs can be realised.
- 6. What is a keeper circuit?
- 7. What is the need for testing in integrated circuits?
- 8. State the general types of fixtures used to test a chip.
- 9. What is a Net in Verilog? What is its default value?
- 10. Write the verilog code to realise a 2 to 1 MUX using gate level modelling.

PART - B

 $(5\times16=80 \text{ Marks})$

11. a) Derive and explain the expression for drain current of a nMOS transistor.

(OR)

b) Discuss the various steps involved in the fabrication of a CMOS transistor.



12. a) Explain the different types of power dissipation in a CMOS circuit and explain briefly the methods to reduce these powers.

(OR)

- b) Discuss, in detail, the reliability problems that cause integrated circuits to fail permanently.
- 13. a) Explain the working of cascade voltage switch logic with an example. State its advantages and disadvantages.

(OR)

- b) Explain the methods of sequencing blocks of combinational logic. Explain also on maximum and minimum delay constraints that have to be adhered to in one of the above methods.
- 14. a) Explain on the logics of the following methods of testing logic circuits:
 - i) Automatic test pattern generation
 - ii) Adhoc testing
 - iii) Built-in self test
 - iv) IDDQ testing.

 $(4 \times 4 = 16)$

(OR)

b) i) Define observability and controllability.

- ii) Explain, in detail on boundary scan testing.

(12)

15. a) i) Explain the components of a verilog module.

(8)

ii) Explain tasks and functions in verilog.

(8)

(OR)

- b) i) What are block statements? How many types of blocks are supported by verilog for a ripple carry counter? (6)
 - ii) Convert a D flip flop into T flip flop. Design a 4 bit ripple carry counter using T flip-flops and write the verilog code using hierarchical model. (10)

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